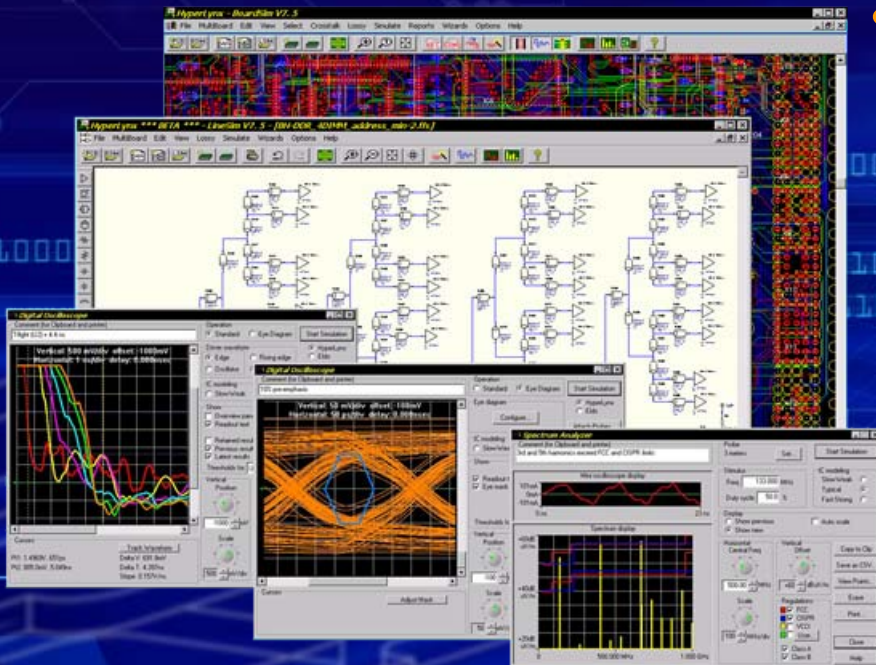


IBIS4.2 and VHDL-AMS for SERDES and DDR2 Analysis



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IBIS 4.2 Multi-lingual Extensions

- **Traditional IBIS lacks the ability to adequately model the behavior of devices used in state of the art communication channels:**
 - Drivers with pre-compensation
 - Receivers with input slew rate sensitivity.
 - Phase locked loop clock and data recovery
 - Simple and adaptive equalization
 - Multi-level signaling
- **Traditional IBIS also lacks the ability to adequately specify new measurements:**
 - Differential overshoot
 - Eye masks
- **IBIS 4.2 Multi-lingual Extensions can address both of these limitations**

SPICE as an IBIS 4.2 Multi-lingual option

- **Good supply of transistor level models for older devices**
 - May be encrypted and therefore not portable between tools
- **Poor standardization**
 - Lots of proprietary primitives
- **Extremely slow simulation**
 - Particularly when using transistor level models
- **Missing a high level view**
 - Needed to effectively model complex digital logic
 - Needed to make complex measurements.

AMS as an IBIS 4.2 Multi-lingual option

- **VHDL-AMS and Verilog-AMS International standards**
 - IEEE and Accellera
- **Fast.**
 - Models are compiled to machine code just like built in primitives.
 - Digital content is handled in event driven kernel
- **Flexible**
 - Can provide both behavior and measurement.
- **Accurate**
 - Uses the same analog non-linear solver as SPICE

IBIS 4.2 Multi-lingual Case Studies

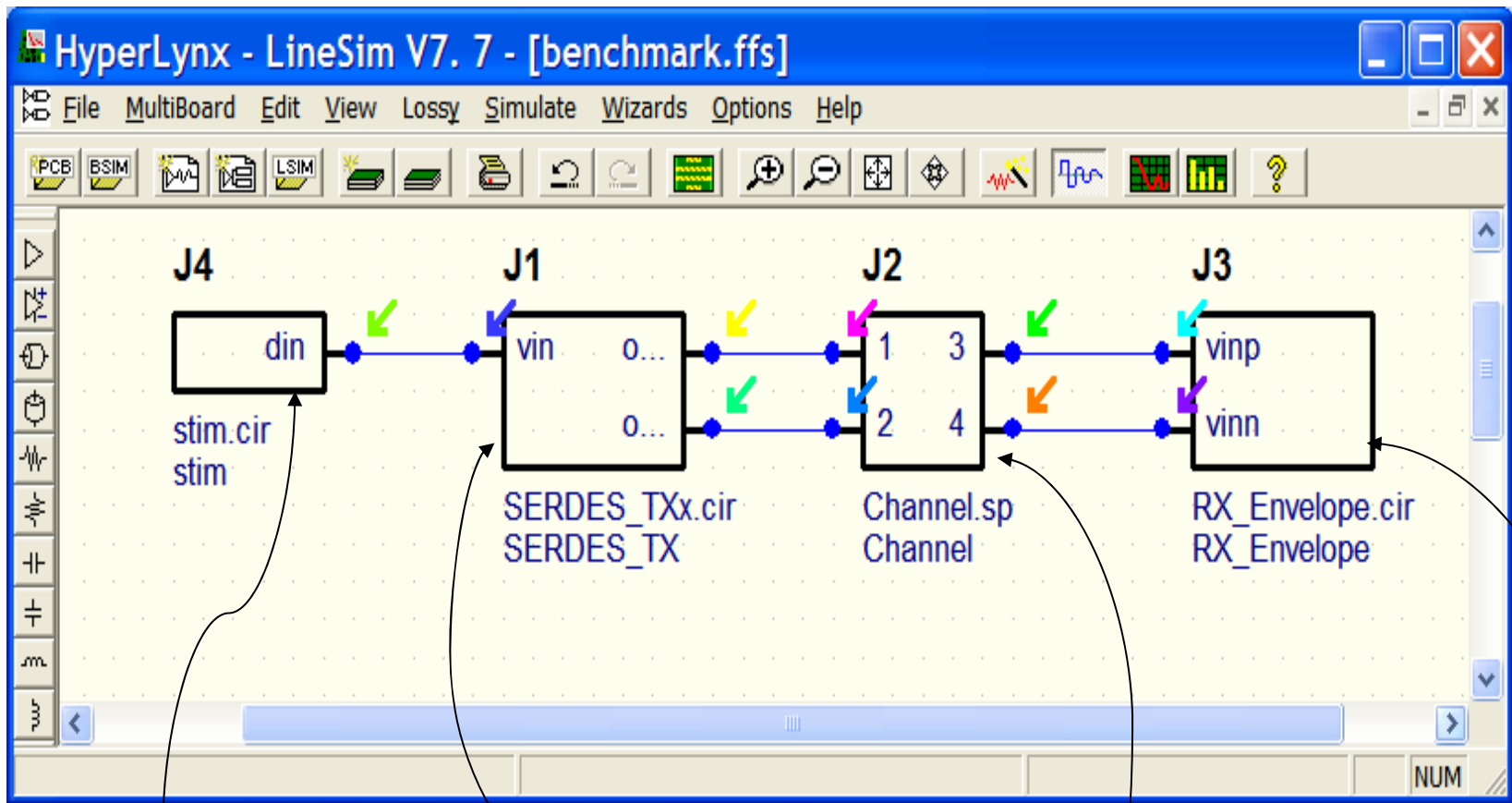
- The model maker and user can best decide whether it is best to create models using the IBIS 4.2 multi-lingual extensions utilizing SPICE or AMS
- The best solution for the SI Engineer may well be a tool that supports the mixing of both
- AMS provides some unique features so this presentation is going to provide two case studies that highlight these features.

AMS Case Study One

Full non-linear analysis of a SERDES channel

- Simulate to 10 million data bits
- Custom data pattern
- VHDL-AMS Driver with non-linear drive characteristics and pre-compensation
- Realistic S-Parameter model for packages, two connectors and backplane*
- VHDL-AMS receiver model with built in envelope recorder
- Simulations to be done on an average single processor notebook computer running Microsoft Windows
- Appropriate simulation time-step for accurate results

* As with previous examples used in presentations, this S-parameter model was provided by an independent third party and not optimized for simulation speed



AMS PRBS Generator

AMS SERDES TX

S-Parameter TX Package, Stub, Connector, Backplane, Connector, Stub, RX Package

AMS RX and Envelope Generator

The VHDL-AMS SERDES Transmitter Model

begin

-- output the proper current based on the state of signal din,
-- and values of constants Ipe and Imain

if domain = quiescent_domain **use** -- if DC then

itxp == Ipe/2.0; itxn == Ipe/2.0; -- set both outputs to half

elsif din='1' **and** din'delayed(bit) = '0' **use**

itxp == Ipe; itxn == 0.0; -- first pulse (txp positive)

elsif din='1' **and** din'delayed(bit) = '1' **use**

itxp == Imain; itxn == Ipe-Imain; -- normal pulse (txp positive)

elsif din='0' **and** din'delayed(bit) = '1' **use**

itxp == 0.0; itxn == Ipe; -- first pulse (txn positive)

elsif din='0' **and** din'delayed(bit) = '0' **use**

itxp == Ipe-Imain; itxn == Imain; -- normal pulse (txn positive)

end use;

break on din, din'delayed(bit) ; -- deal with the discontinuities

-- P and N-side C_comp, R_term, Vdd

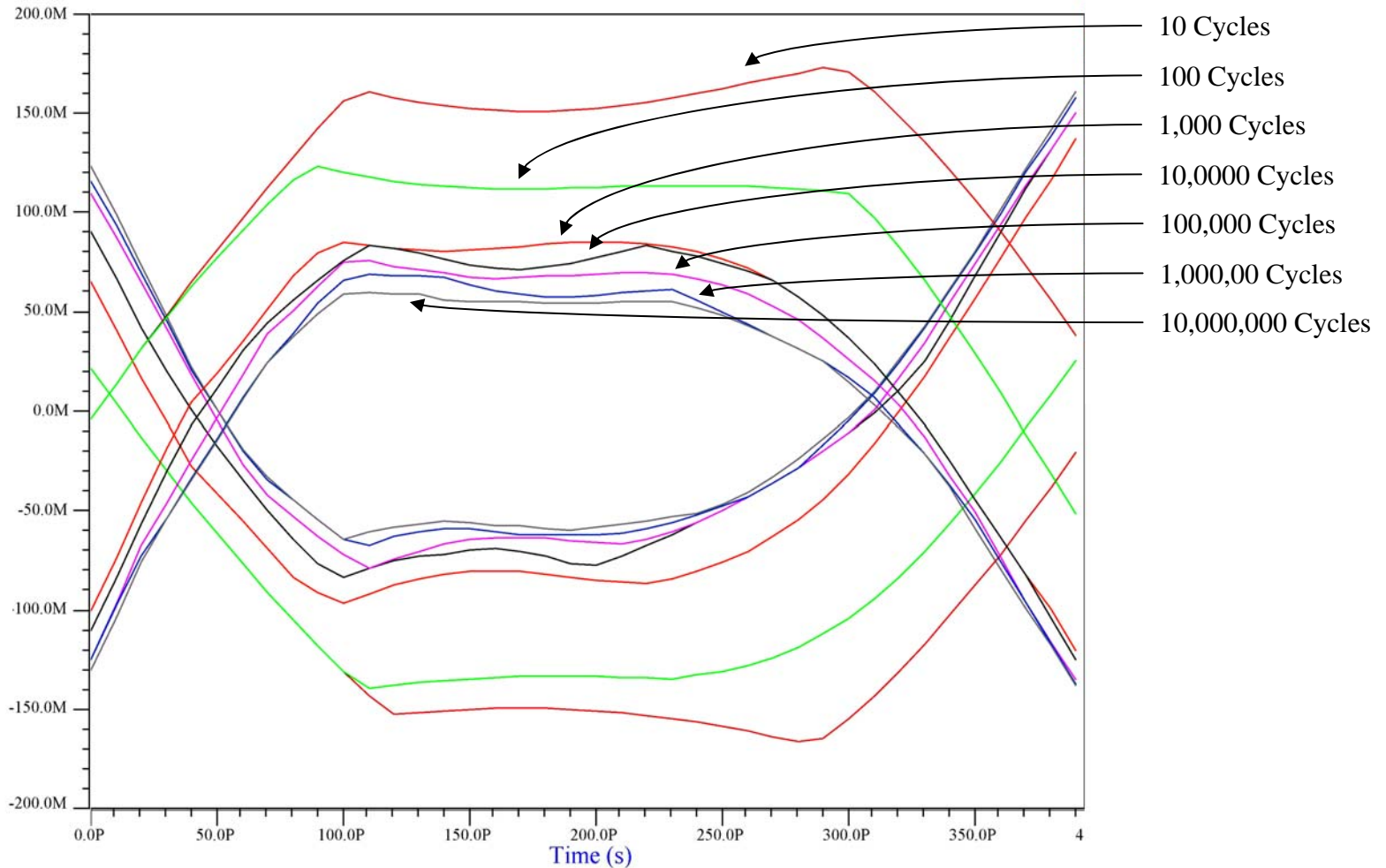
i_r_term_p == (vtxp - Vdd)/R_term; i_c_comp_p == c_comp * vtxp'dot;

i_r_term_n == (vtxn - Vdd)/R_term; i_c_comp_n == c_comp * vtxn'dot;

end architecture;



Results: Simulation to 10 Million Data Cycles (All simulations completed overnight)



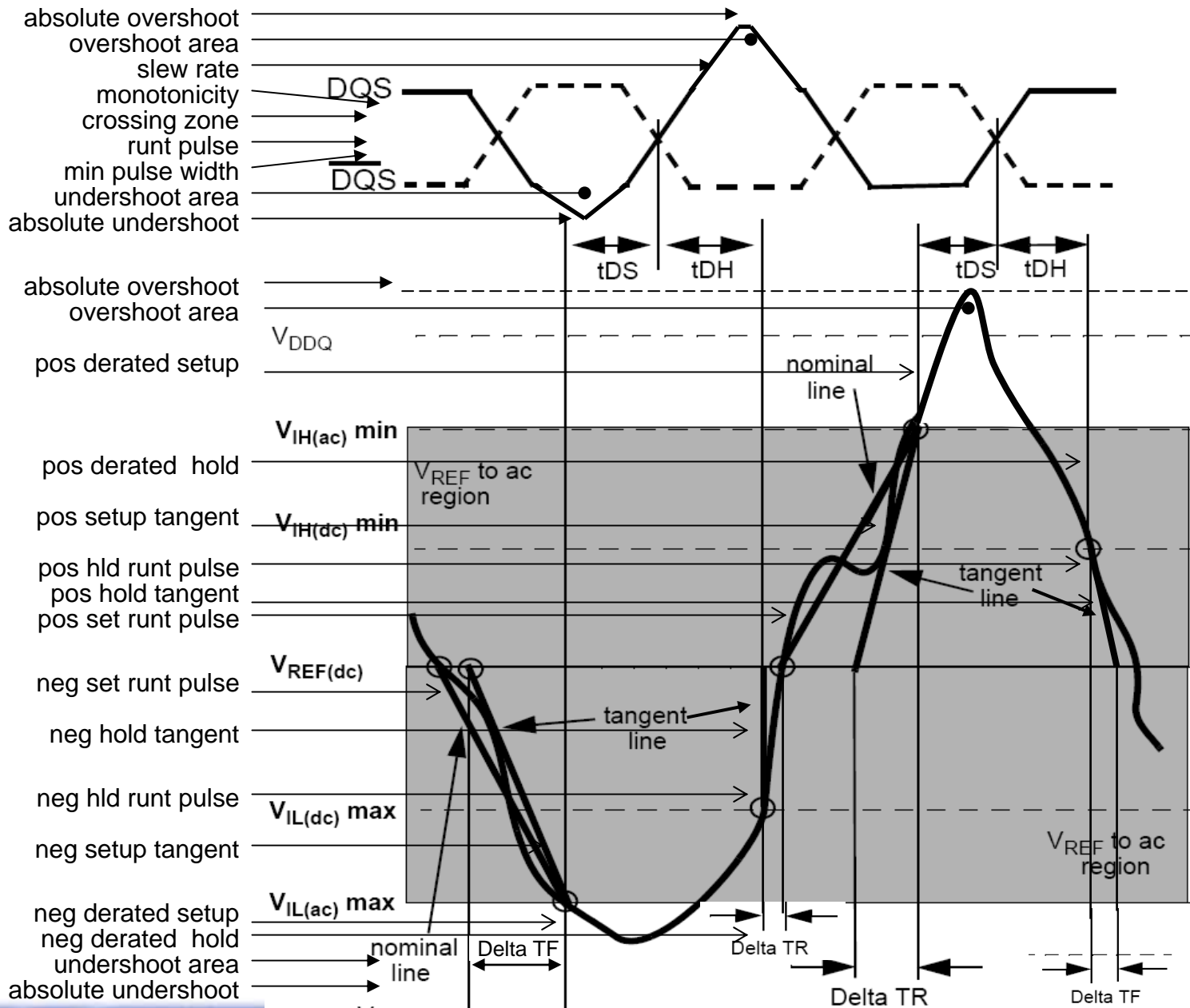
AMS Case Study Two

Automated DDR2 Measurements

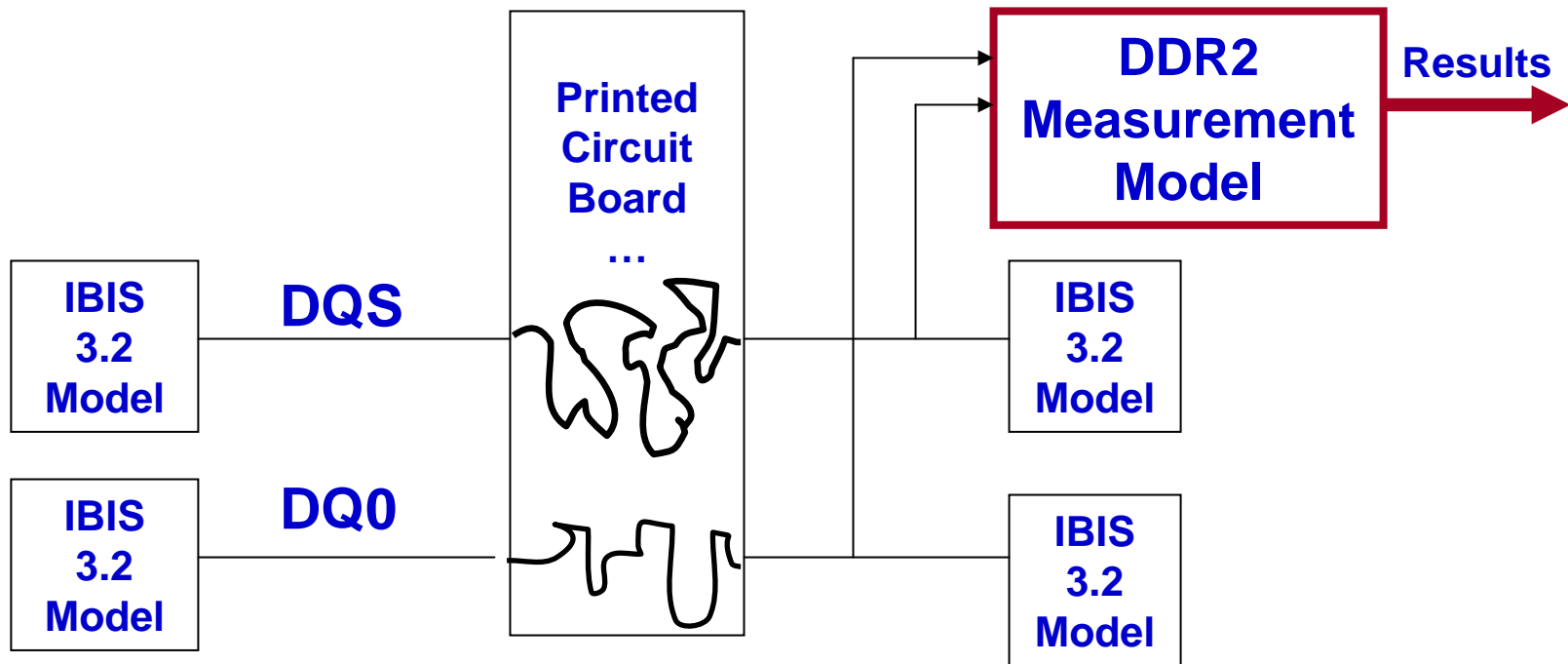
- Implement all measurements specified in the DDR2 datasheet in a VHDL-AMS model
- Utilize standard IBIS 3.2 driver and receiver models



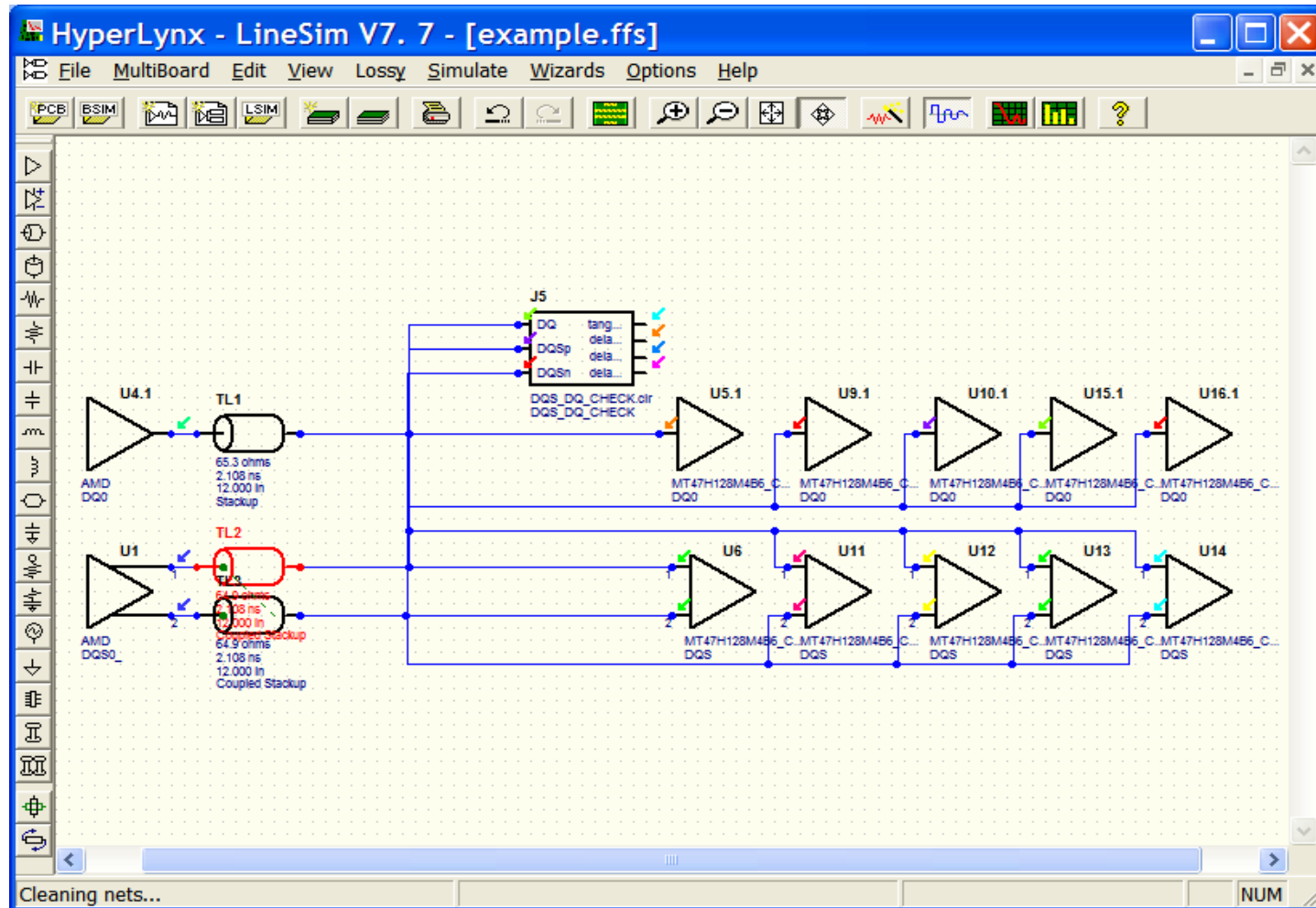
DDR2 Electrical and Timing Constraints



IBIS 4.2 Measurement Model



Pre-layout analysis using the IBIS 4.2 Measurement Model



TANGENT MEASUREMENT

Wait for vref crossing

Store data points

Wait for vix_ac cross

Calculate the slope from each point to the vix_ac crossing point

Return the maximum slope

Wait for vix_dc crossing

Calculate the slope from each subsequent point back to the vix_dc crossing

Wait for vref crossing

Return the max slope

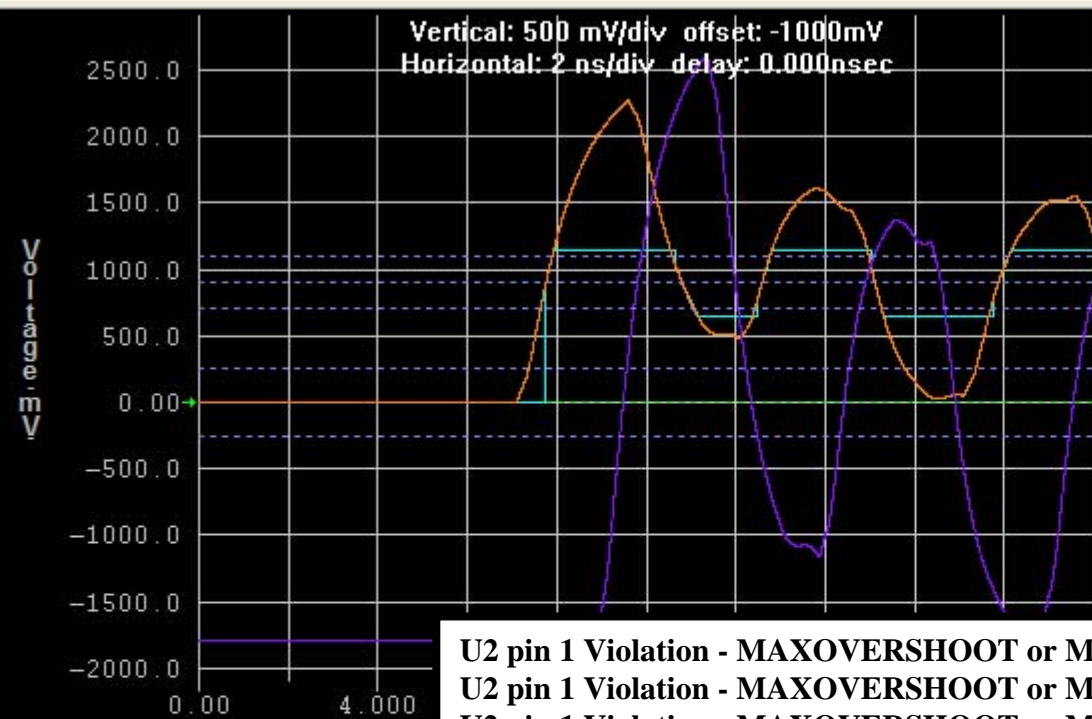
begin

```
-----  
-- measure the setup time tangent  
-----  
wait until VREFDC; -- wait for a crossing of correct direction  
max_slope:=0.0; data_point_cntr:=0; setup_crossing <= 0.0*sec;  
while not vix_ac'event loop -- store all the data points until vix_ac crossing  
    data_point_v(data_point_cntr) := Vin'reference;  
    data_point_t(data_point_cntr) := now;  
    wait on vix_ac, ASP; -- wait for next event  
    data_point_cntr := data_point_cntr + 1;  
end loop; -- go on to find the maximum slope  
setup_crossing <= now;  
for i in min_slope to data_point_cntr-1 loop  
    slope := (crossing_point_v - data_point_v(i)) /  
             (crossing_point_t - data_point_t(i));  
    if slope > max_slope then max_slope:=slope; end if;  
end loop;  
setup_slope <= max_slope;  
-----  
-- measure the hold tangent  
-----  
wait until not vix_dc; -- wait for opposite crossing of vix_dc  
max_slope := 0.0;  
crossing_point_v := Vin'reference; crossing_point_t:=now;  
-- calculate slope of each point until vix_dc, or max_points  
while not VREFDC'event loop  
    wait on VREFDC, ASP ;  
    slope := -(Vin'reference - crossing_point_v) /  
             (now - crossing_point_t);  
    if slope > max_slope then max_slope := slope; end if;  
end loop;  
hold_slope <= max_slope; -- in v/s  
end process;
```

(error and exception handling removed for clarity)



Comment (for Clipboard and printer)



Operation
 Standard Eye Diagram Start Simulation

Driver waveform
 Edge MHz HyperLynx
 Oscillator Duty Eldo/ADMS

IC modeling
 Slow-Weak Typical Fast-Strong

Show
 Overview pane Readout text
 Loaded results Previous results Latest results

Probes:
 Located:

Visibility
 Voltage Current

Zoom

Pins

Pin	Signal	Color
J5	delay...	Orange
	delay...	Pink
	delay...	Blue
	DQ (...)	Green
	pps	Red

Cursors

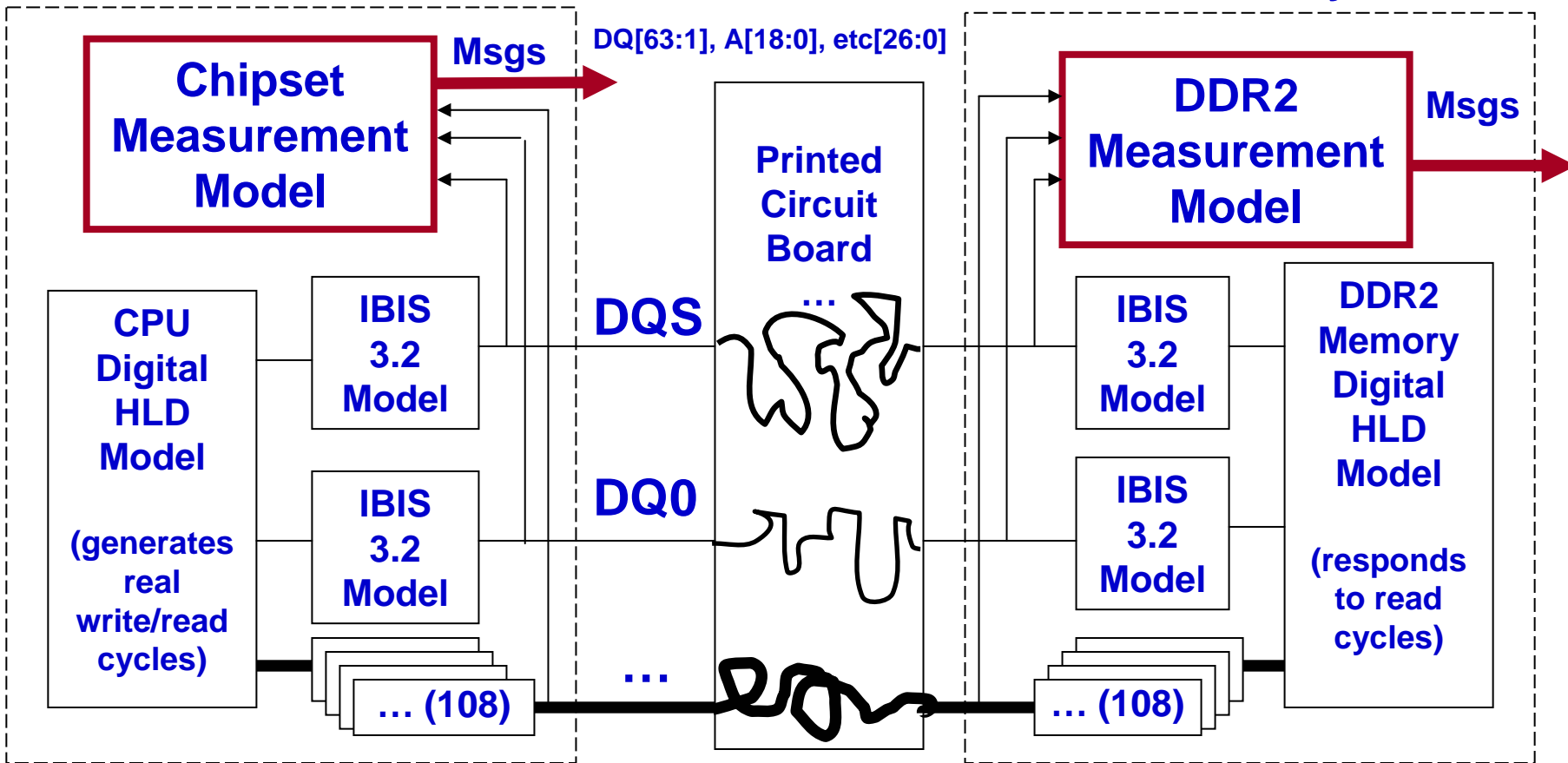
Measurements
 Entire Region Waveform

U2 pin 1 Violation - MAXOVERSHOOT or MAXUNDERSHOOT Level Exceeded at time: 2337
 U2 pin 1 Violation - MAXOVERSHOOT or MAXUNDERSHOOT Level Exceeded at time: 4790
 U2 pin 1 Violation - MAXOVERSHOOT or MAXUNDERSHOOT Level Exceeded at time: 7290
 U2 pin 1 Violation - MAXOVERSHOOT or MAXUNDERSHOOT Level Exceeded at time: 9815
 U2 pin 1 Violation - MAXOVERSHOOT or MAXUNDERSHOOT Level Exceeded at time: 12294
 U2 pin 1 Violation - MAXOVERSHOOT or MAXUNDERSHOOT Level Exceeded at time: 14816
 U2 pin 1 Violation - MAXOVERSHOOT or MAXUNDERSHOOT Level Exceeded at time: 17293
 U2 pin 1 Violation - MAXOVERSHOOT or MAXUNDERSHOOT Level Exceeded at time: 19816
 U2 pin 2 Violation - DQS exceeded VIXACMIN at Differential Crossing at time: 1275
 U2 pin 2 Violation - DSQ exceeded VINDCMAX or VINDCMIN at time: 5914
 U2 pin 2 Violation - DSQ exceeded VINDCMAX or VINDCMIN at time: 5955
 U2 pin 1 Setup Check PASSED. Expected: 0.275 ns. Actual: 1.55 ns at time: 4536
 U2 pin 2 Warning: dqs slew value out of range of table.
 dqs_slew= 4.33e+9. Max table index value= 4.00e+009 at time: 5799
 U2 pin 2 Warning: dq slew value out of range of table.
 dq_slew= 3.566e+9. Max table index value= 2.00e+009 at time: 5799
 U2 pin 1 Hold Check PASSED, Expected: 0.32 ns. Actual: 1.177 ns. at time: 5799

Model for the Full DDR2 Channel Integrating both Behavior and Measurement *

IBIS 4.2 Chipset Model

IBIS 4.2 Memory Model



* Note: This model is not in strictly IBIS 4.2 compliant because it uses an external circuit that references an IBIS 3.1 model

Special thanks to

Randy Wolff and his associates at Micron for assistance in developing DDR2 simulation and measurement models.



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